TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74ACT521P,TC74ACT521F

8-Bit Equality Comparator

The TC74ACT521 is an advanced high speed CMOS 8-BIT DIGITAL COMPARATOR fabricated with silicon gate and double-layer metal wiring C²MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

This device may be used as a level converter for interfacing TTL or NMOS to High Speed CMOS. The inputs are compatible with TTL, NMOS and CMOS output voltage levels.

It compares two 8-bit binary or BCD words applied inputs $P_0\sim P_7$, and inputs $Q_0\sim Q_7$, and indicates whether or not they are equal.

A signal active low enable is provided to facilitate cascading of several packages to compare of words greater than 8 bits.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

Features

- High speed: $t_{pd} = 6.4 \text{ ns (typ.)}$ at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $ICC = 8 \mu A \text{ (max)}$ at $Ta = 25^{\circ}C$
- Compatible with TTL outputs: VIL = 0.8 V (max)

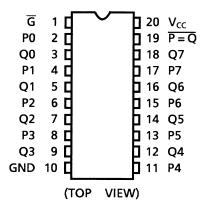
 $V_{IH} = 2.0 \text{ V (min)}$

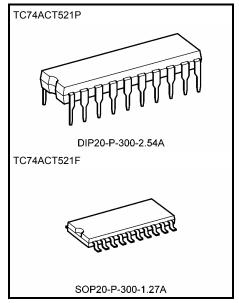
• Symmetrical output impedance: $|I_{OH}| = I_{OL} = 24$ mA (min) Capability of driving 50 Ω

transmission lines.

- Balanced propagation delays: $t_{pLH} \simeq t_{pHL}$
- Pin and function compatible with 74F521

Pin Assignment

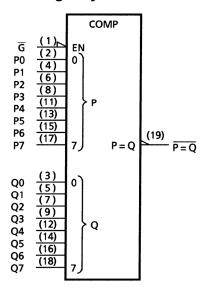




Weight

DIP20-P-300-2.54A : 1.30 g (typ.) SOP20-P-300-1.27A : 0.22 g (typ.)

IEC Logic Symbol

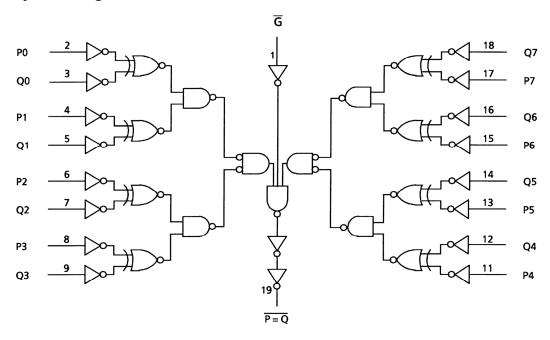


Truth Table

Inp	uts	Output				
P, Q	IG	$\overline{P} = Q$				
P = Q	L	L				
P ≠ Q	L	Н				
Х	Н	Н				

X: Don't care

System Diagram



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Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	-0.5~7.0	V
DC input voltage	V _{IN}	-0.5~V _{CC} + 0.5	V
DC output voltage	V _{OUT}	-0.5~V _{CC} + 0.5	٧
Input diode current	Ι _{ΙΚ}	±20	mA
Output diode current	lok	±50	mA
DC output current	I _{OUT}	±50	mA
DC V _{CC} /ground current	Icc	±100	mA
Power dissipation	P_{D}	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T _{stg}	-65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of $Ta = -40\sim65$ °C. From Ta = 65 to 85°C a derating factor of -10 mW/°C should be applied up to 300 mW.

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V _{CC}	4.5~5.5	V
Input voltage	V _{IN}	0~V _{CC}	V
Output voltage	V _{OUT}	0~V _{CC}	V
Operating temperature	T _{opr}	-40~85	°C
Input rise and fall time	dt/dV	0~10	ns/V

Note: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either VCC or GND.



Electrical Characteristics

DC Characteristics

					Ta = 25°C		Ta = -40~85°C				
Characteristics Symbol	V _{CC} (V)			Min	Тур.	Max	Min	Max	Unit		
High-level input voltage	VIH	_			4.5~ 5.5	2.0	ı	_	2.0		V
Low-level input voltage	V _{IL}	_		4.5~ 5.5	ı	ı	0.8	_	0.8	V	
	V _{OH}	V _{IN} = V _{IH} or V _{IL}	$I_{OH} = -50 \mu A$		4.5	4.4	4.5	_	4.4		
High-level output voltage			$I_{OH} = -24 \text{ mA}$		4.5	3.94	_	_	3.80	_	V
			$I_{OH} = -75 \text{ mA}$	(Note)	5.5	_	_	_	3.85	_	
		V _{IN} = V _{IH} or V _{IL}	$I_{OL} = 50 \ \mu A$		4.5	_	0.0	0.1	_	0.1	
Low-level output voltage	V_{OL}		I _{OL} = 24 mA		4.5	_	_	0.36	_	0.44	V
			$I_{OL} = 75 \text{ mA}$	(Note)	5.5	_	_	_	_	1.65	
Input leakage current	I _{IN}	$V_{IN} = V_{CC}$ or GND			5.5			±0.1	_	±1.0	μА
Quiescent supply current	Icc	V _{IN} = V _{CC} or GND		5.5	_	_	8.0	_	80.0	μΑ	
	Ic	Per input: $V_{IN} = 3.4 \text{ V}$ Other input: V_{CC} or GND		5.5	_	_	1.35	_	1.5	mA	

Note: This spec indicates the capability of driving 50 Ω transmission lines.

One output should be tested at a time for a 10 ms maximum duration.

AC Characteristics ($C_L = 50$ pF, $R_L = 500 \Omega$, input: $t_r = t_f = 3$ ns)

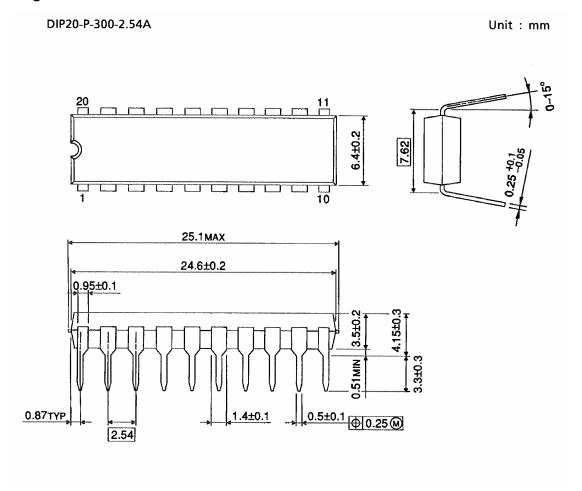
Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = -40~85°C		Unit
	Symbol	rest Condition	V _{CC} (V)	Min	Тур.	Max	Min	Max	Offic
Propagation delay time $ (Pn, Qn-\overline{P=Q}) $	t _{pLH}	_	5.0 ± 0.5	_	7.1	11.4	1.0	13.0	ns
Propagation delay time (\overline{G} - \overline{P} = \overline{Q})	t _{pLH}	_	5.0 ± 0.5	_	5.7	8.3	1.0	9.5	ns
Input capacitance	C _{IN}	_		_	5	10	_	10	pF
Power dissipation capacitance	C _{PD} (Note)			_	29	_	_		pF

Note: CPD is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$ICC (opr) = CPD \cdot VCC \cdot fIN + ICC$$

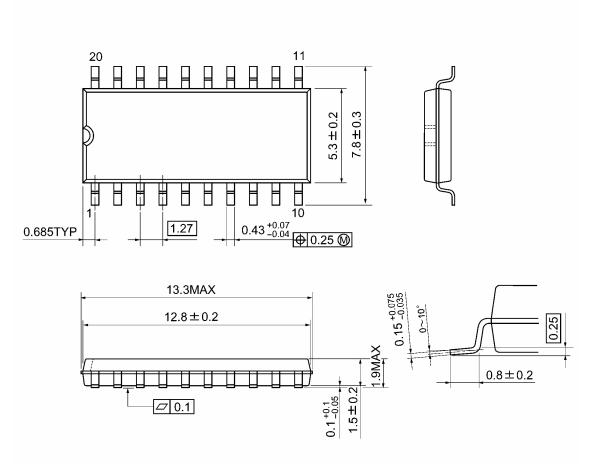
Package Dimensions



Weight: 1.30 g (typ.)

Package Dimensions

SOP20-P-300-1.27A Unit: mm



Weight: 0.22 g (typ.)

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20070701-EN GENERAL

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